

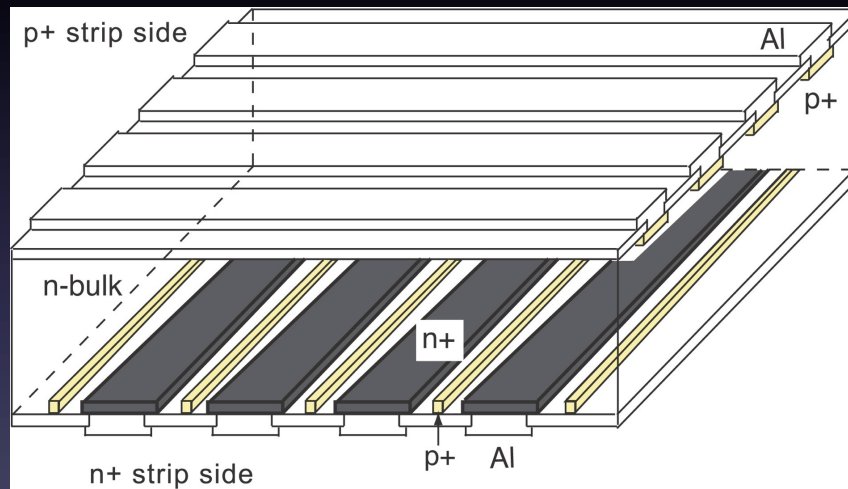
Updates on the front-end electronics for the microstrip sensors of the MVD

MVD meeting, Alba 29 April 2013

INFN-Sezione di Torino

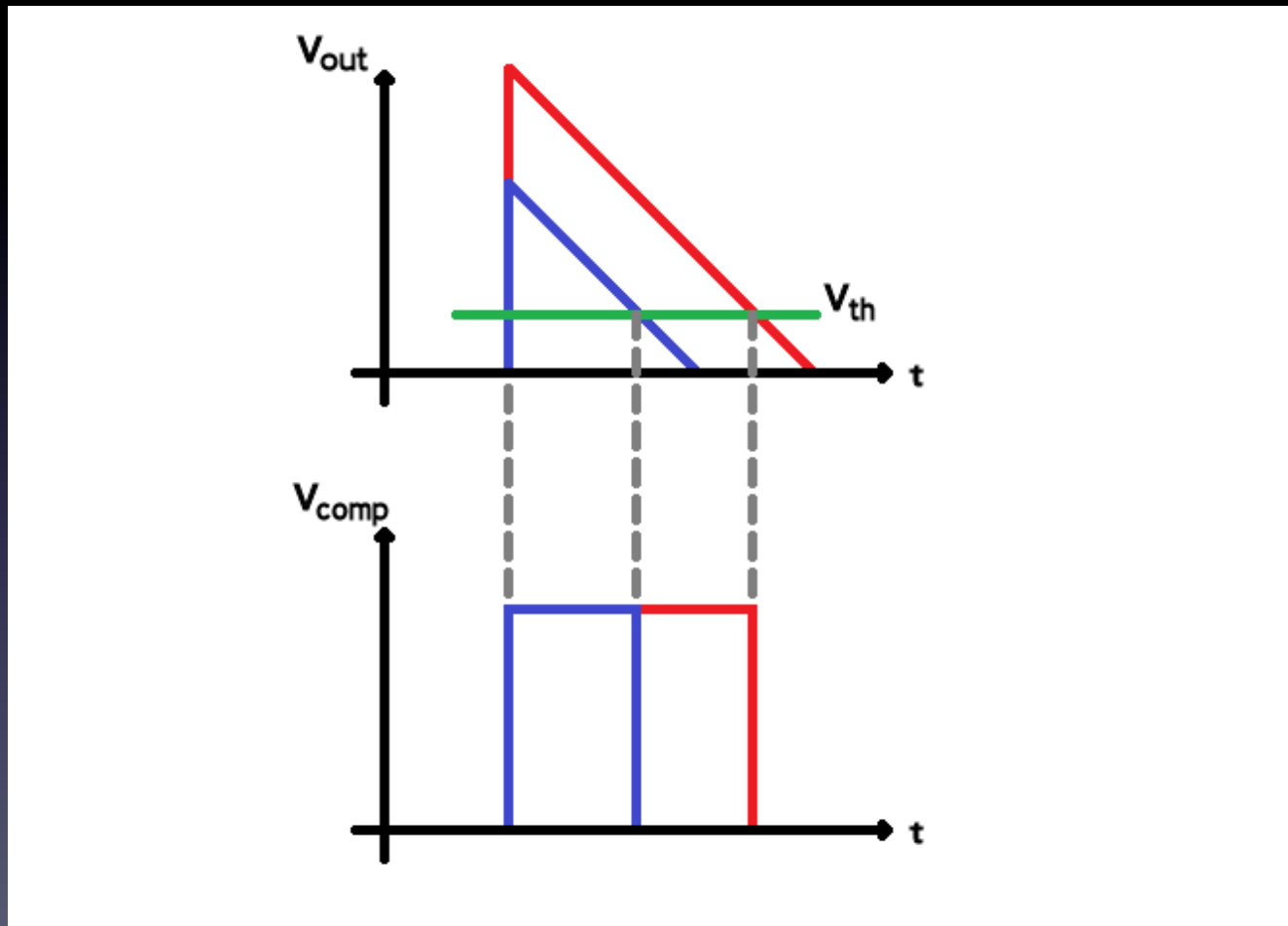
Speaker: Valentino Di Pietro

Microstrip Sensors requirements



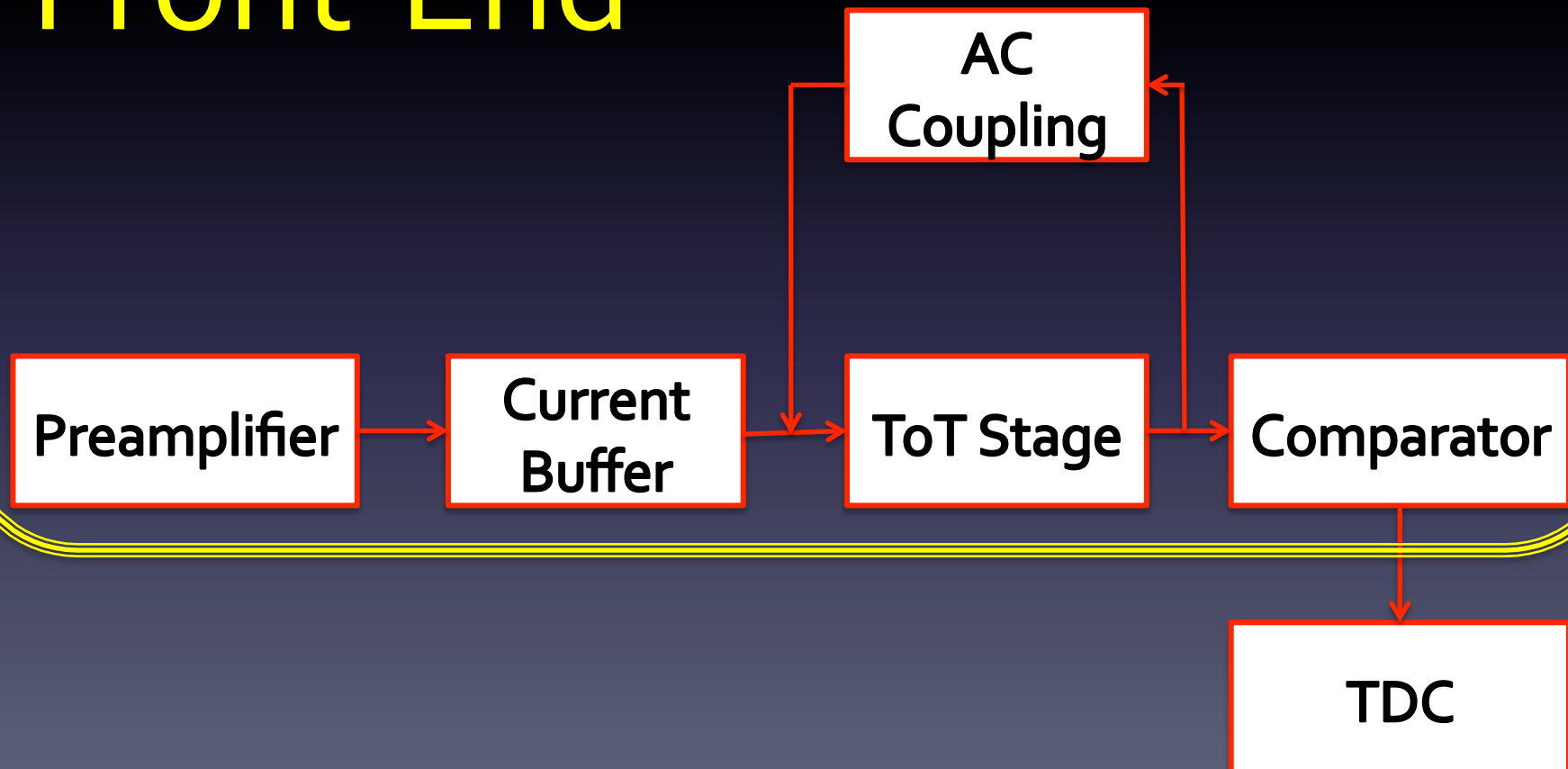
- Specifications
 - Length ~ 8-10 cm
 - Width ~ 60-80 μm
 - Pitch ~ 100 μm
 - $C_{\text{det}} \sim 5-30 \text{ pF}$
- Goals
 - Dynamic range ~ 9 bits
 - Noise < 2000 e^-
 - Power consumption $\leq 4 \text{ mW/ch}$

ToT technique

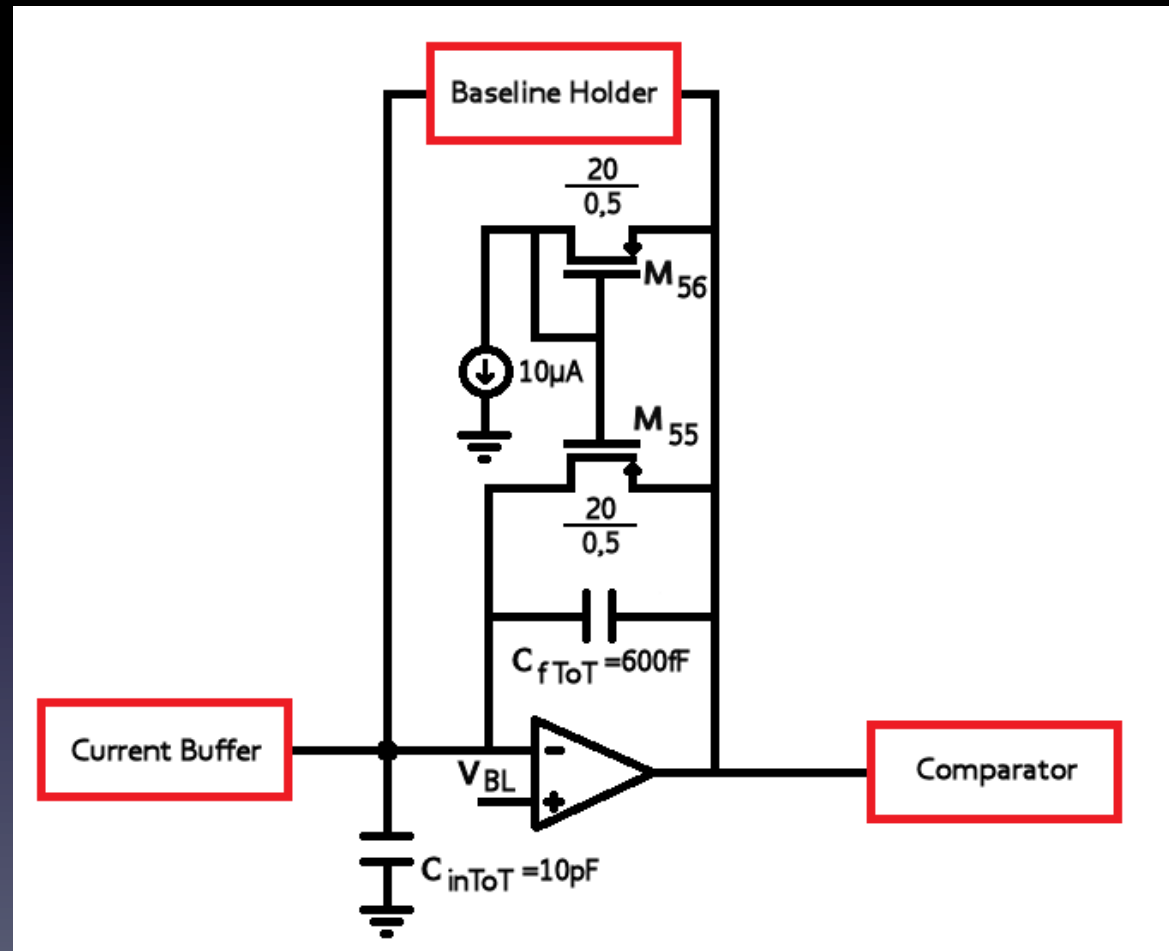


Implemented input stage

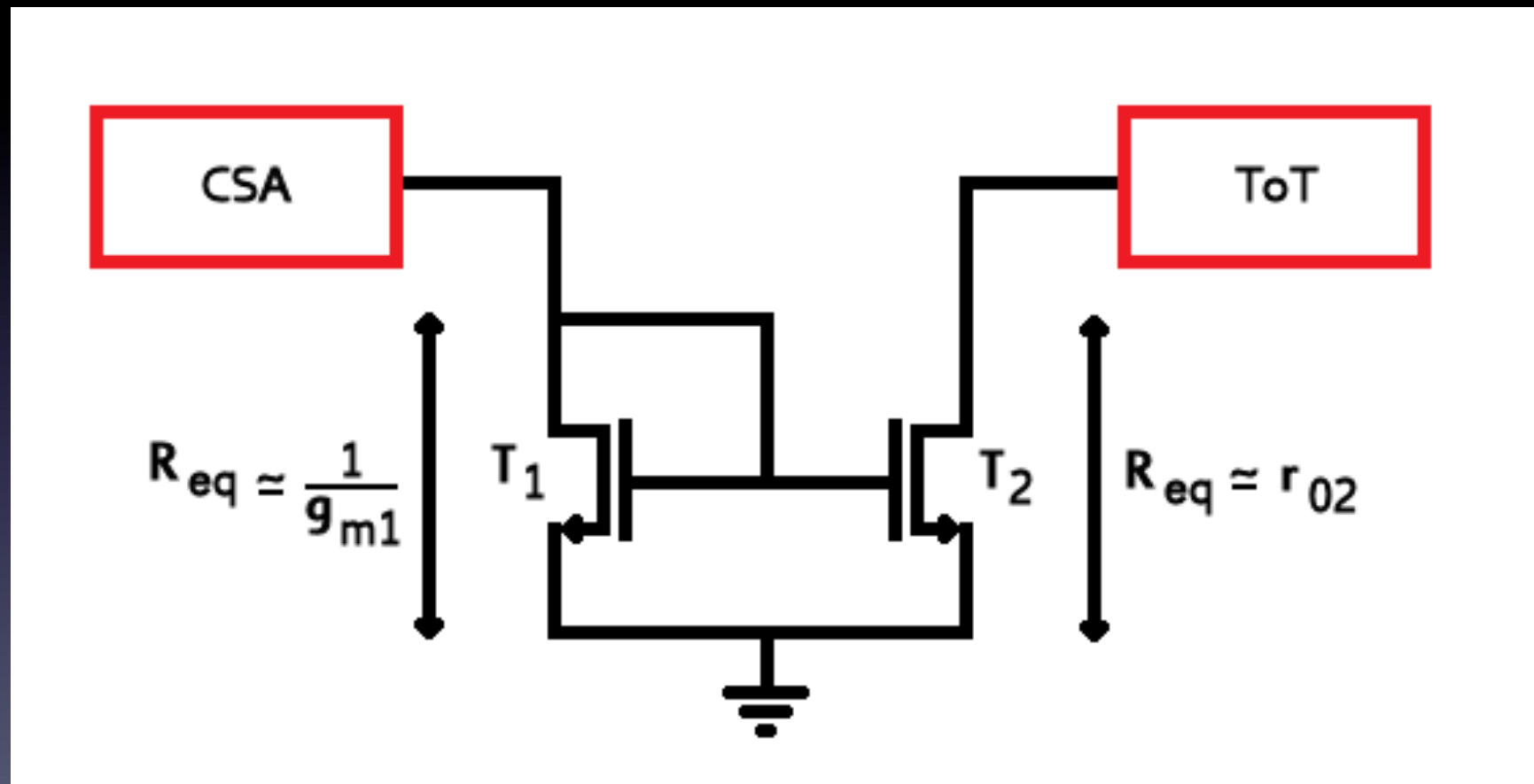
Front-End



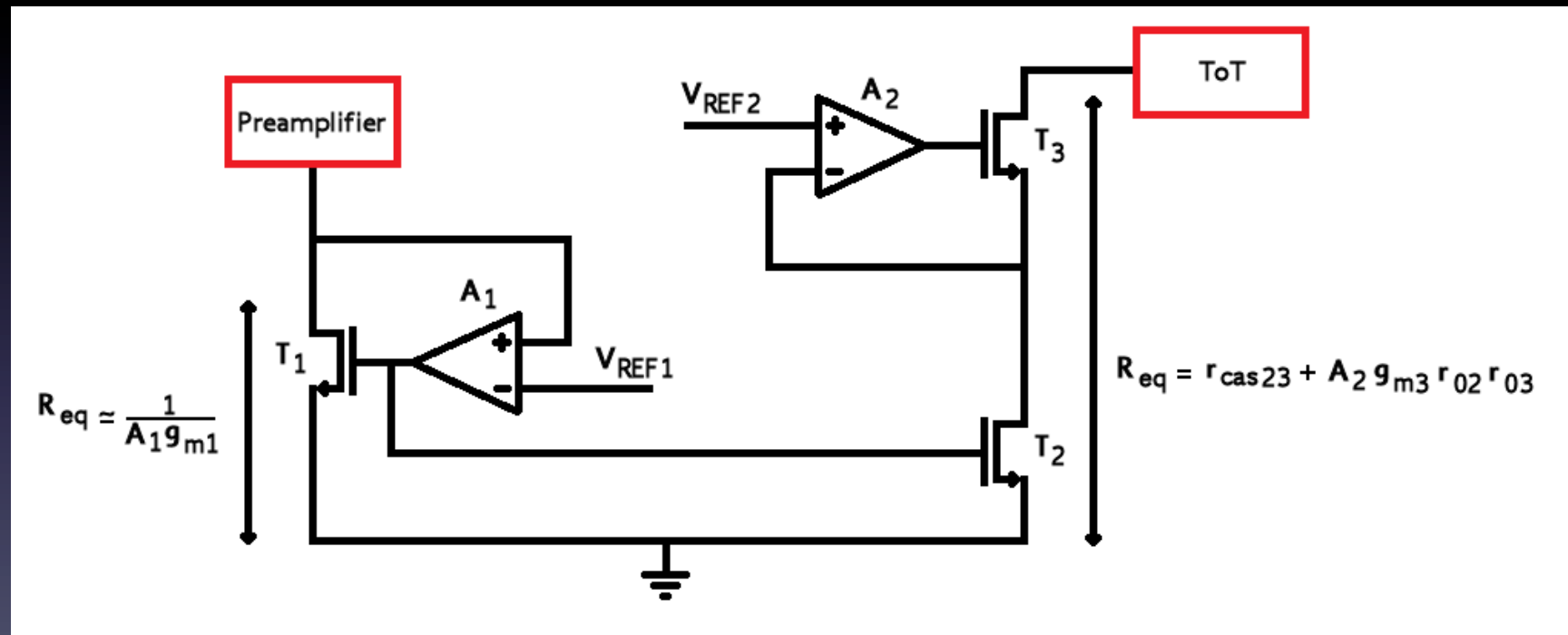
Implemented FE stage: ToT Stage



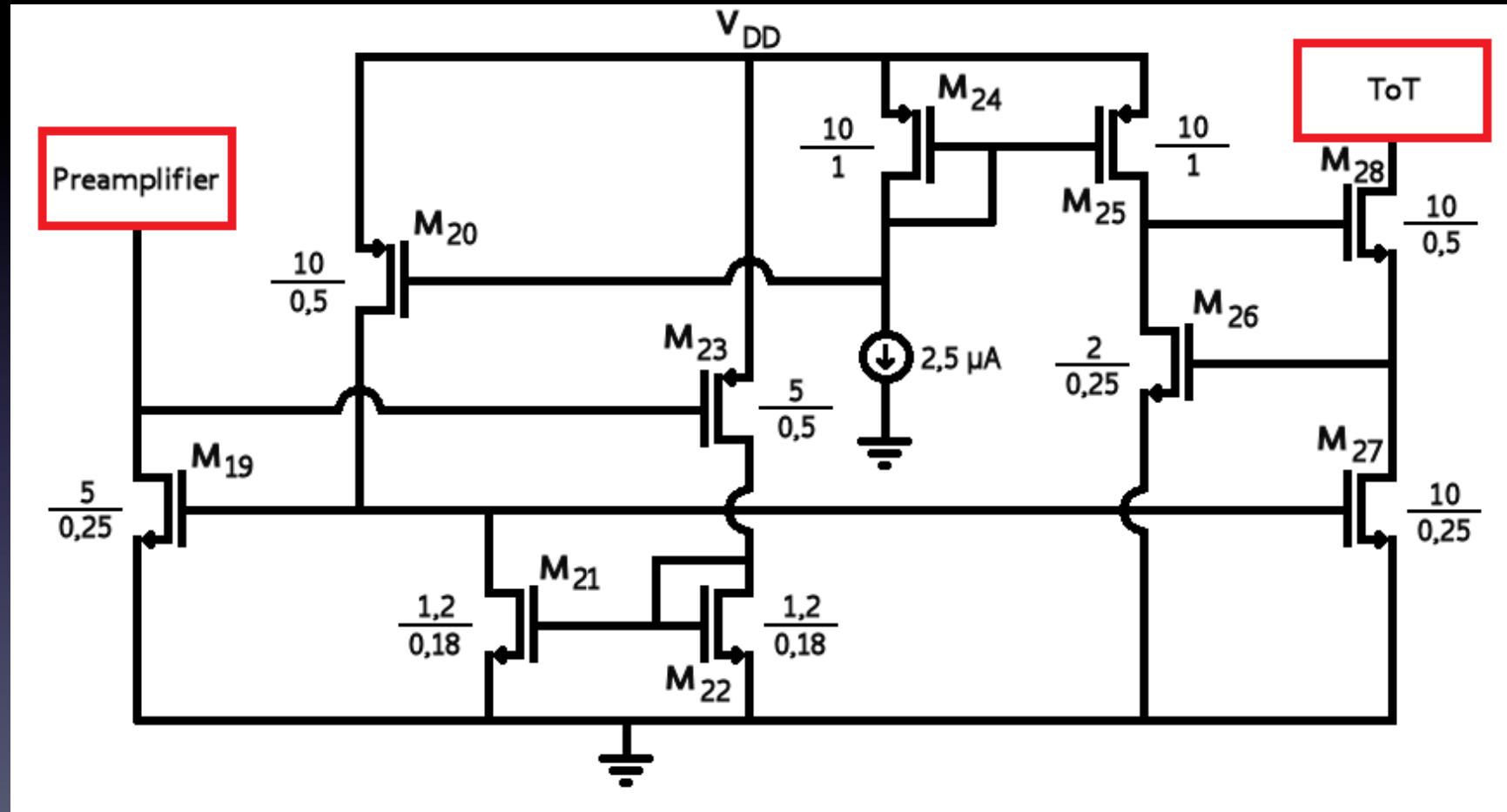
Current Buffer



Current Buffer with g_m -boosting

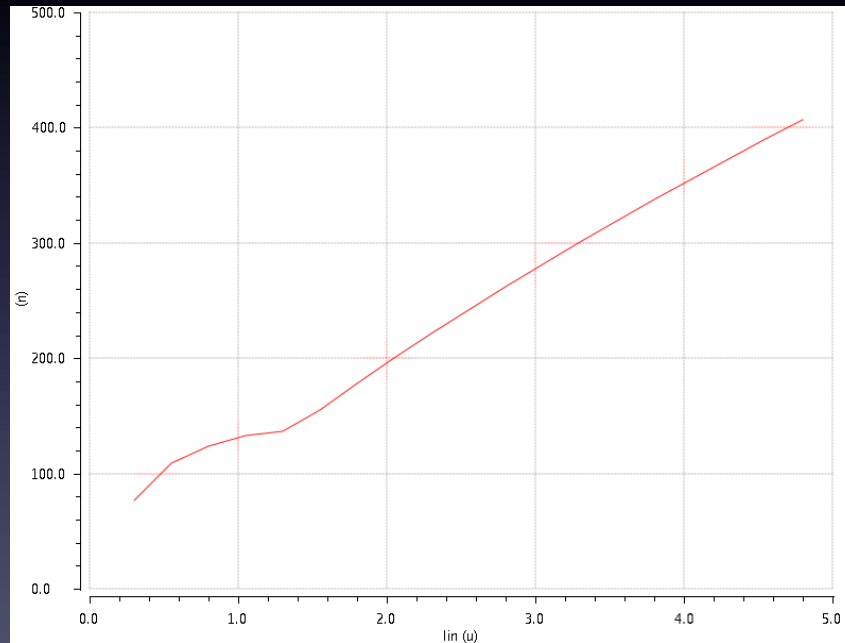


Implemented FE stage: Current Buffer

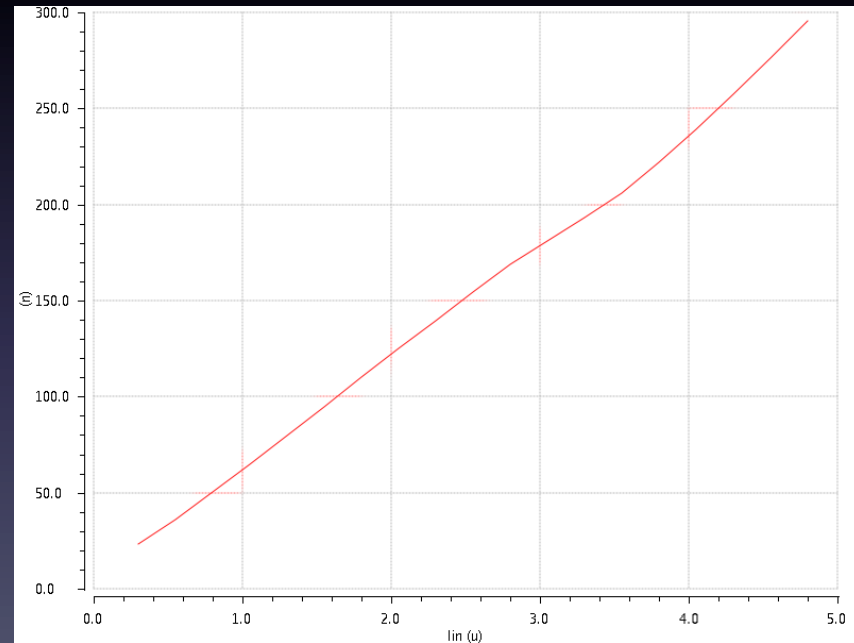


Simulations: Current Buffer

Without g_m -boosting

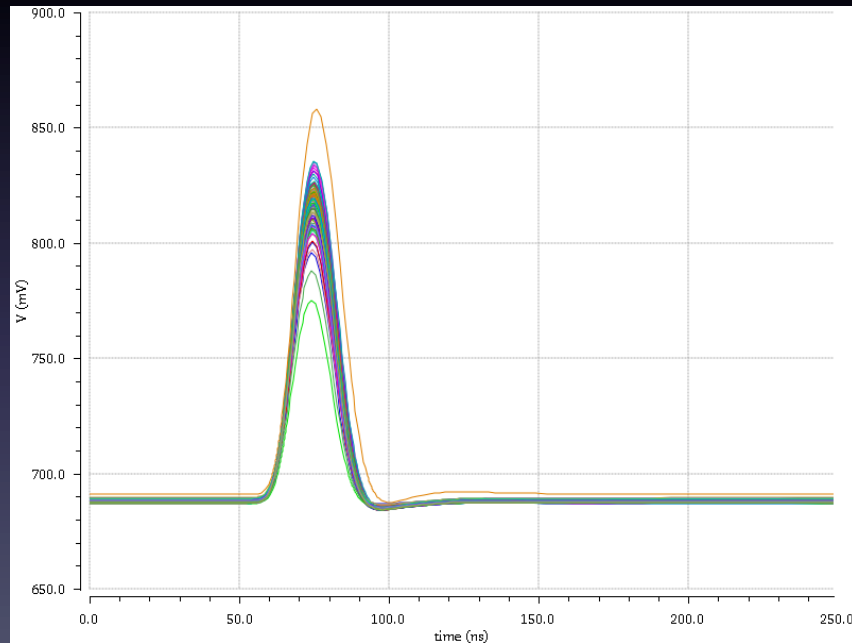


With g_m -boosting

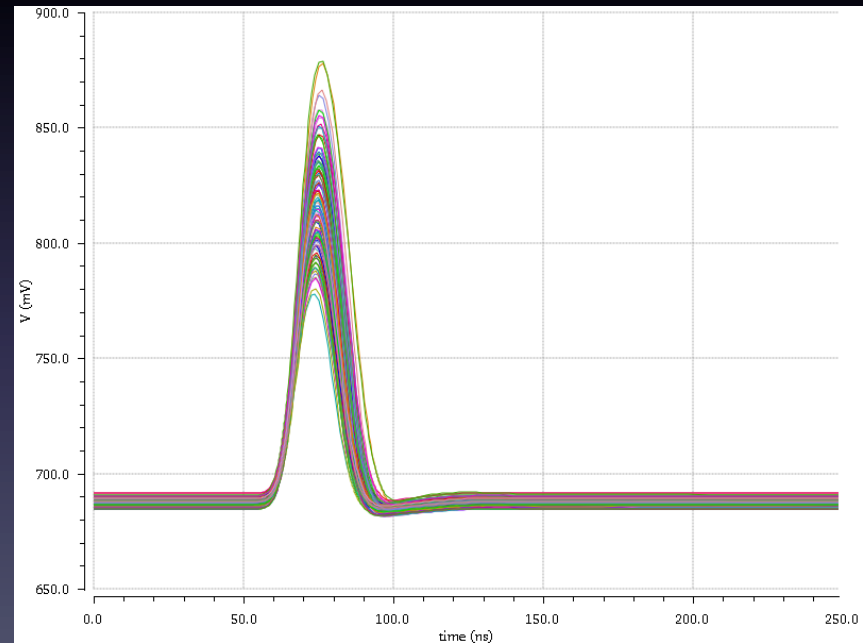


Simulations: Monte Carlo (1)

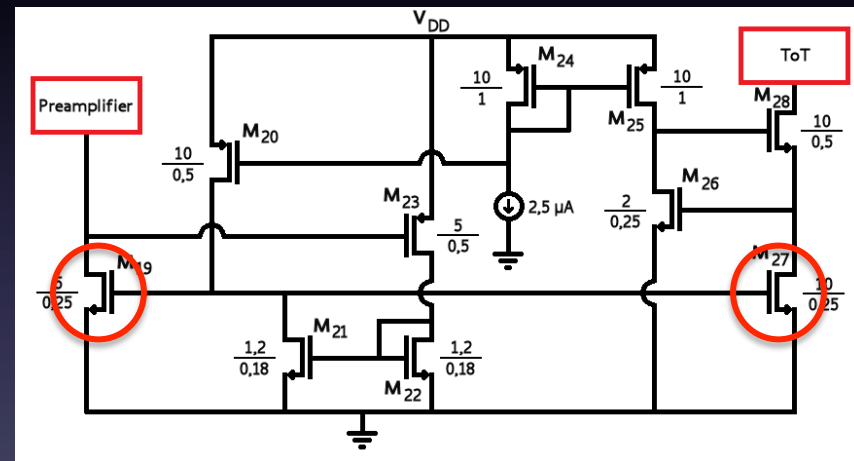
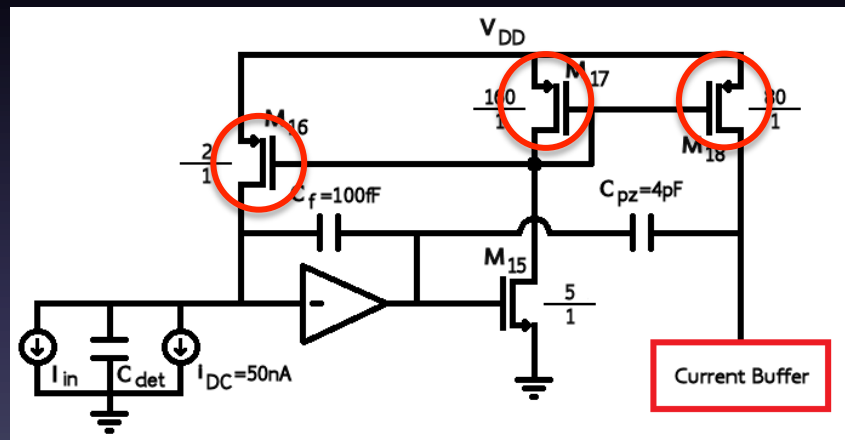
Process variations



Mismatch variations

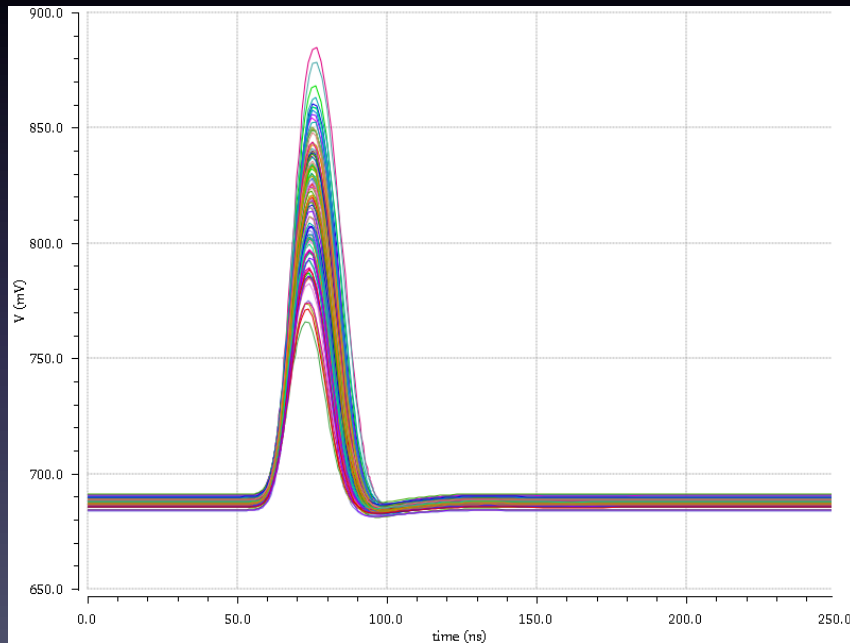


Simulations: Monte Carlo (2)

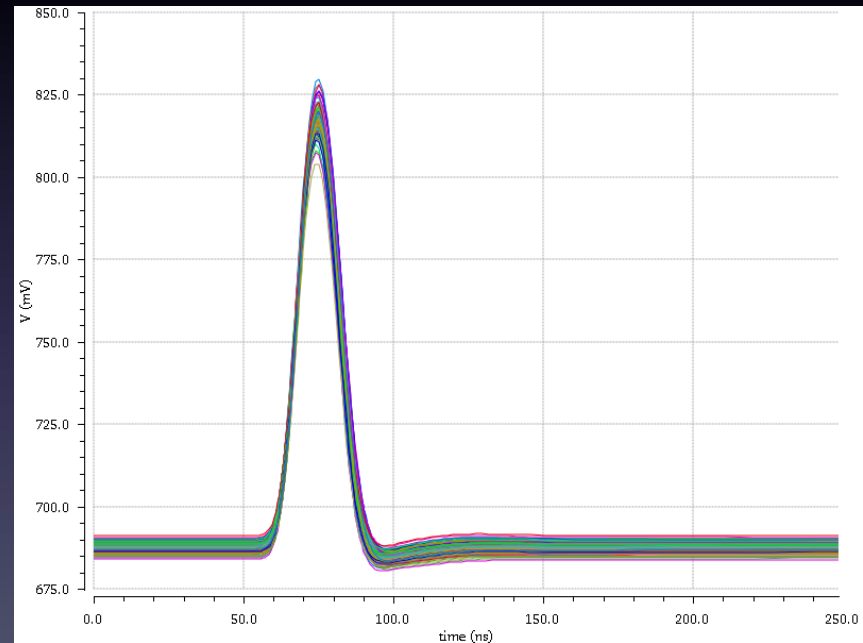


Simulations: Monte Carlo (3)

MC without input biasing current mirror

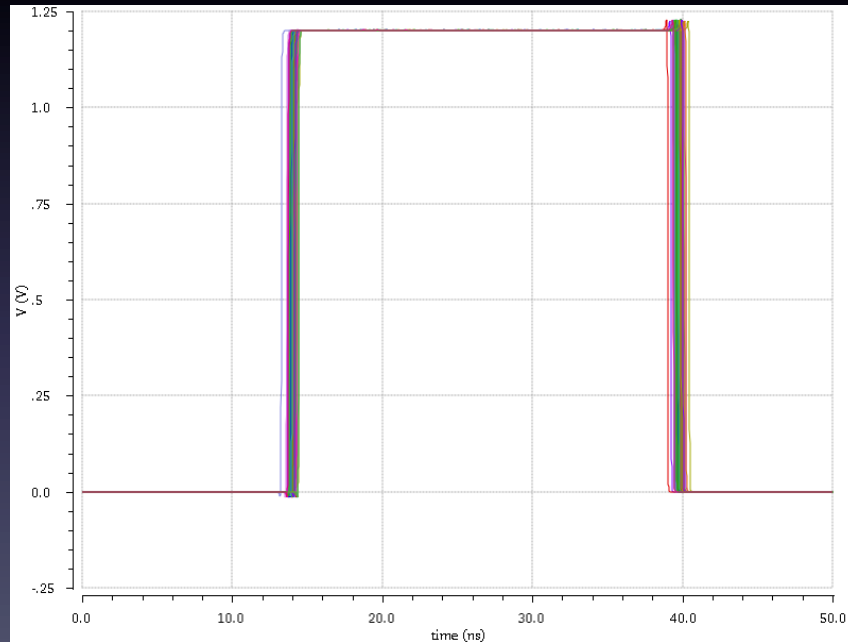


MC without current buffer current mirror



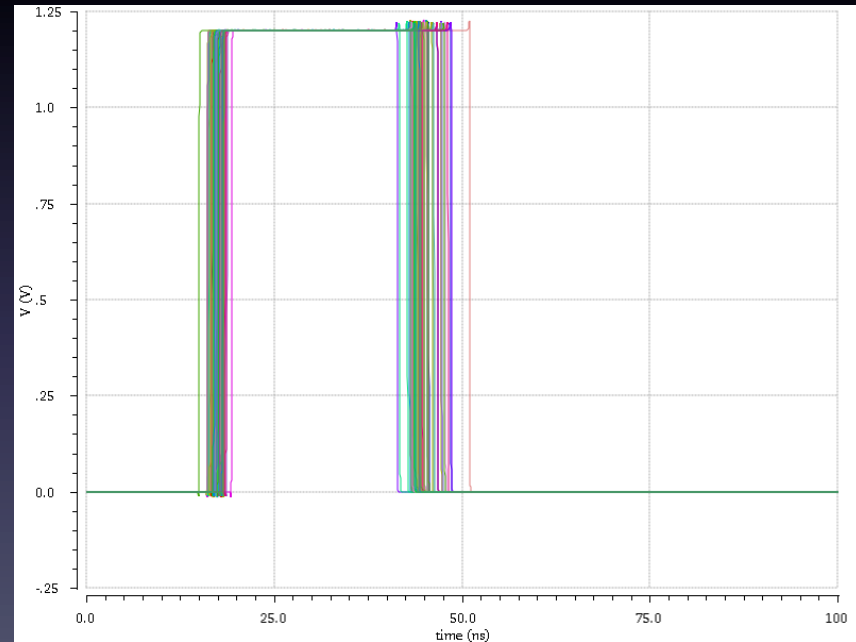
Simulations: Jitter

$C_{\text{det}} = 5 \text{ pF}$



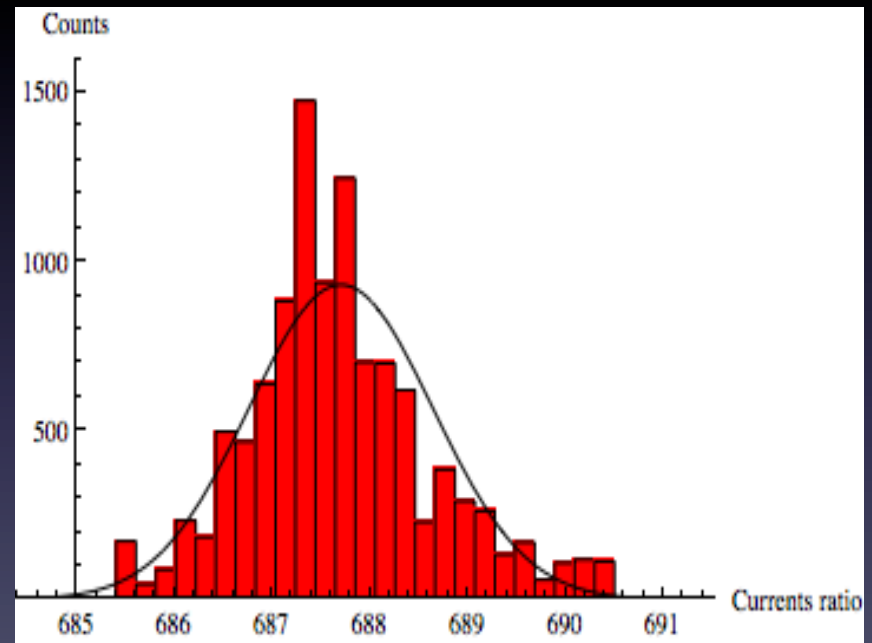
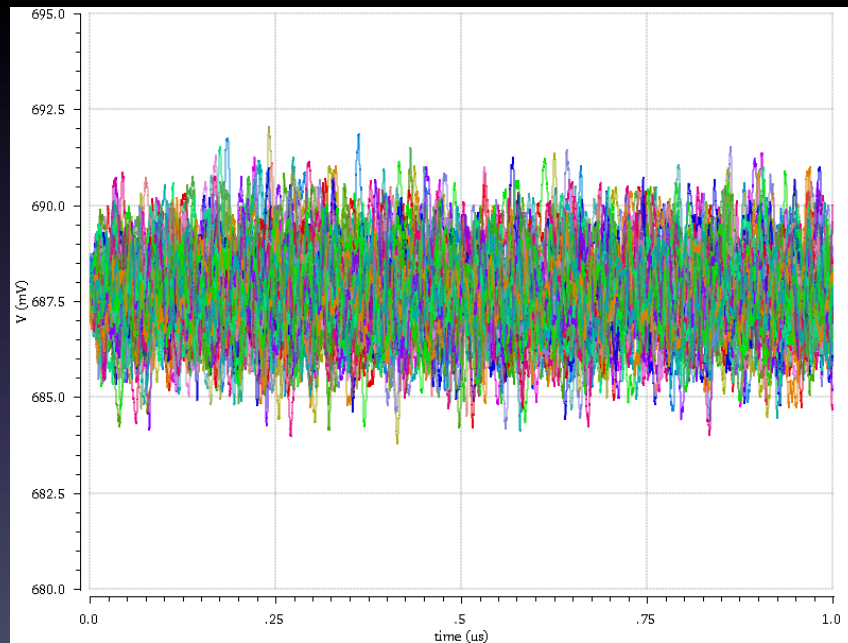
$\sigma_t \sim 300 \text{ ps}$

$C_{\text{det}} = 30 \text{ pF}$

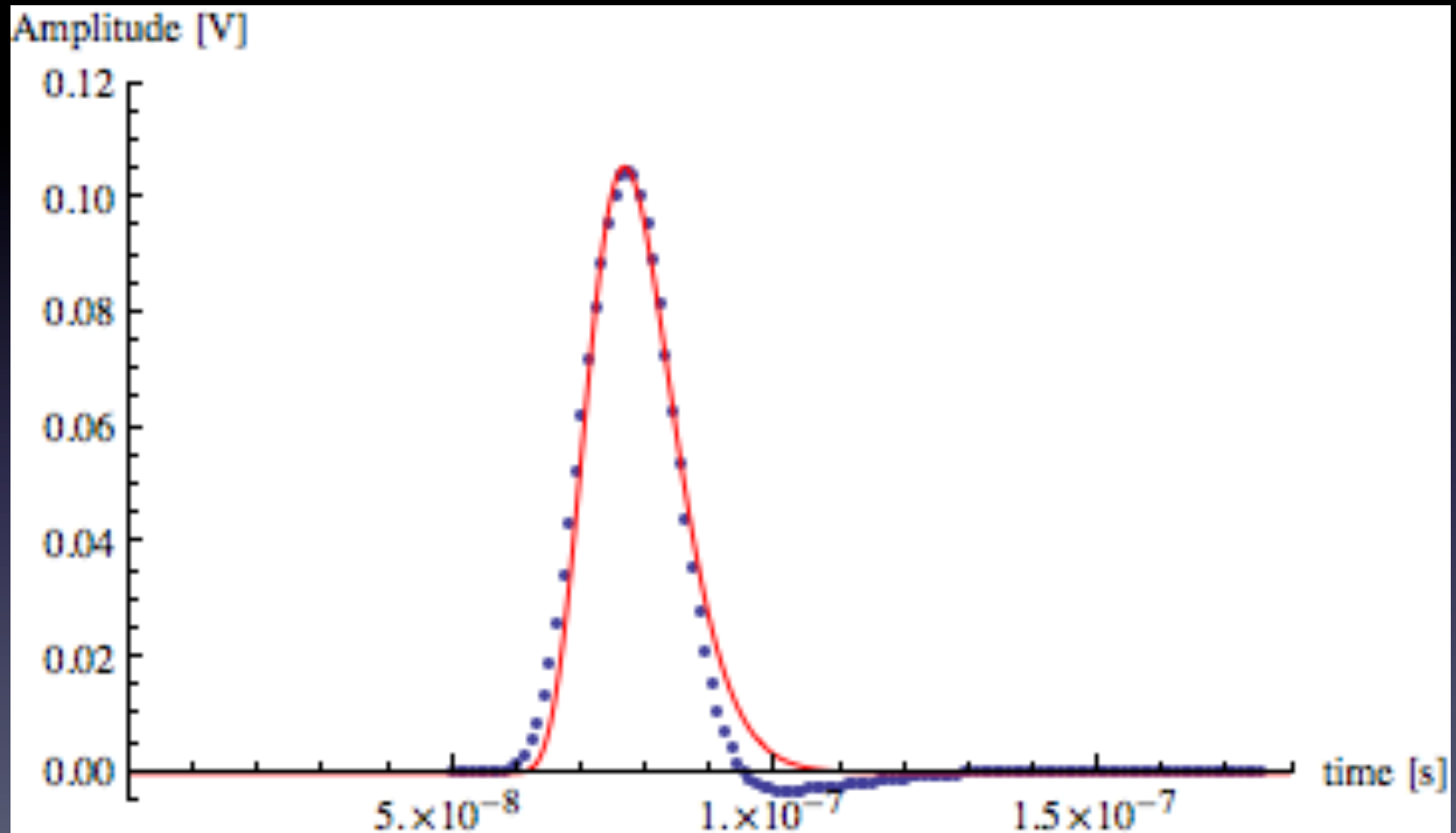


$\sigma_t \sim 1.5 \text{ ns}$

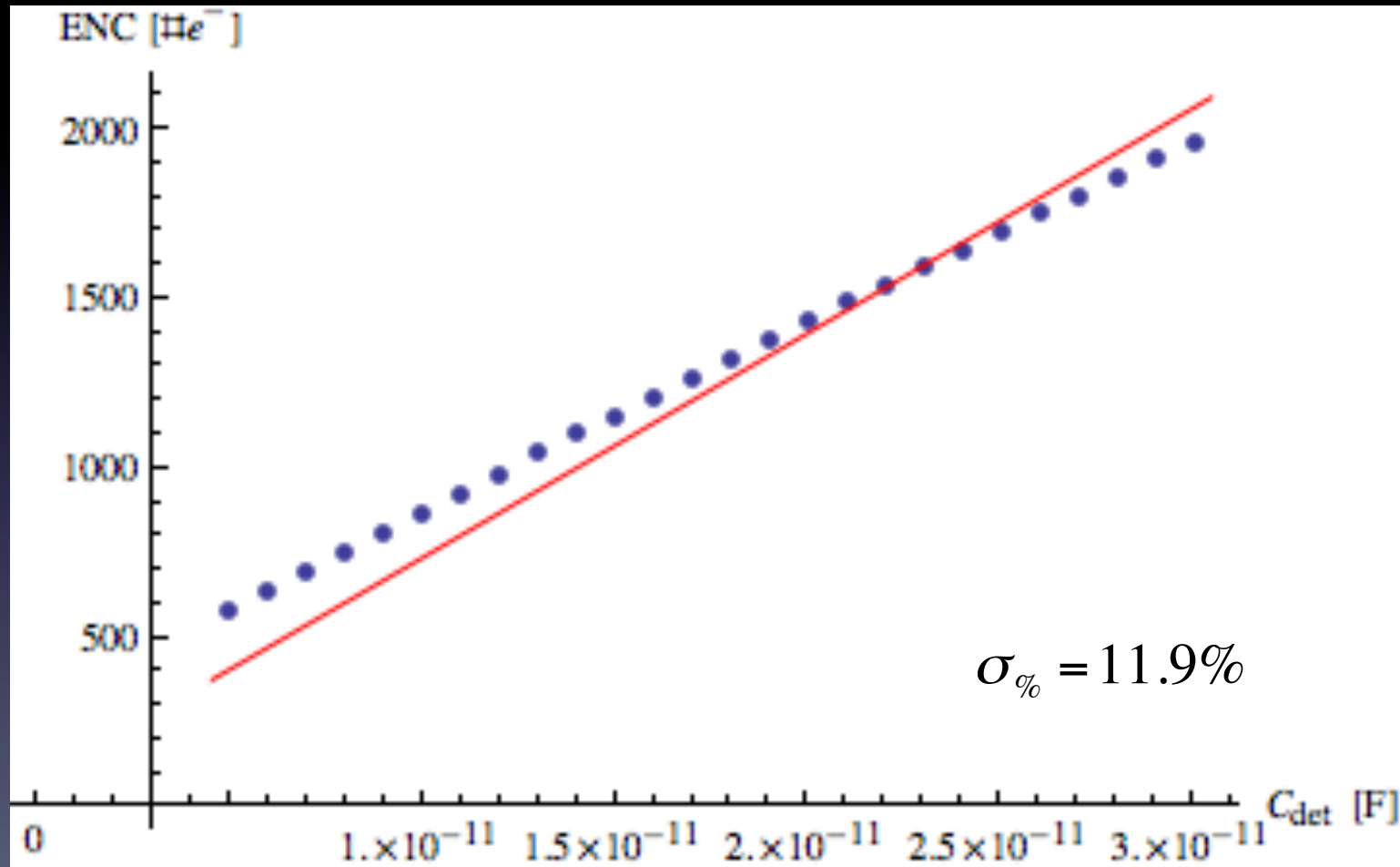
Simulations: Noise (1)



Simulations: Noise (2)



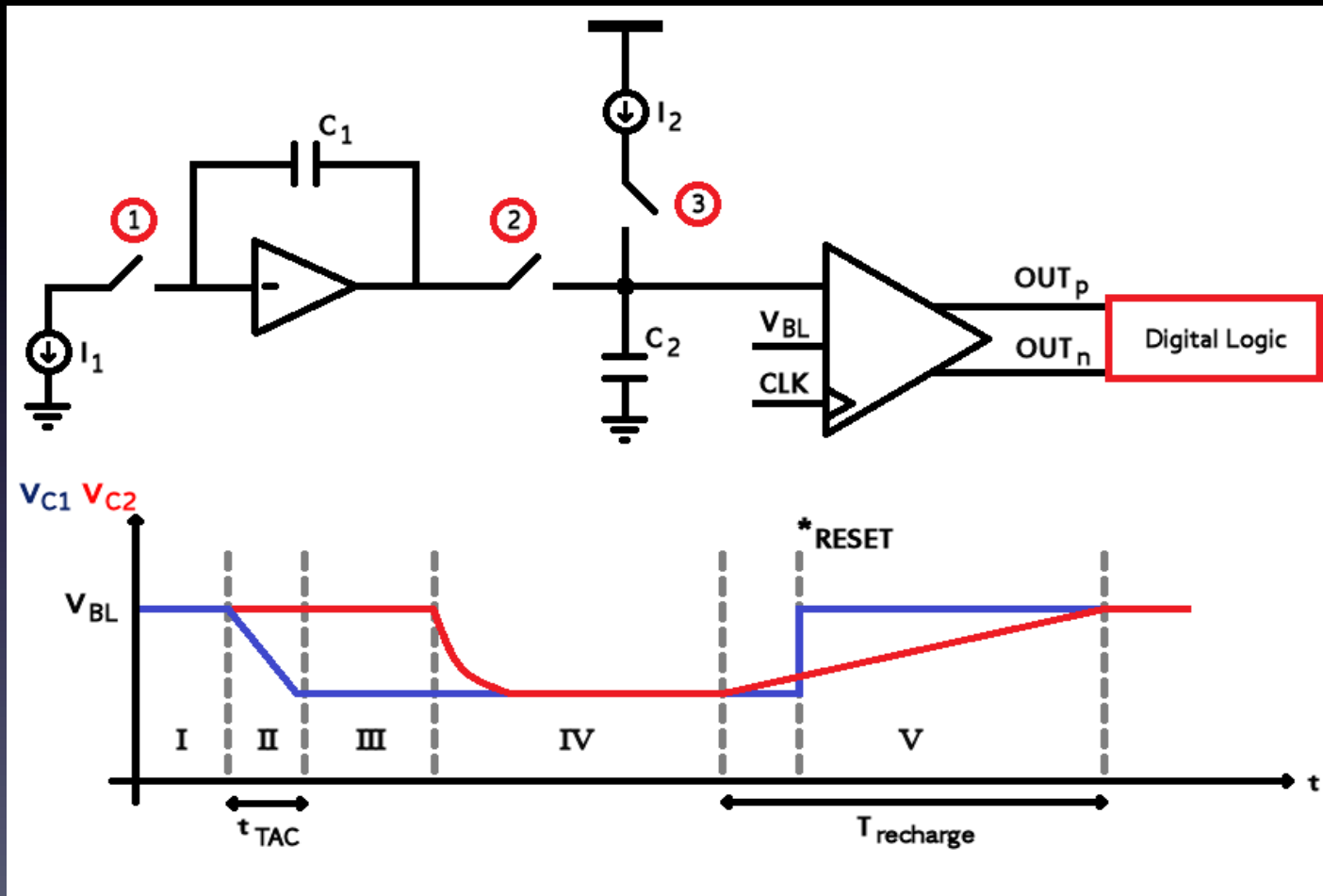
Simulations: Noise (3)



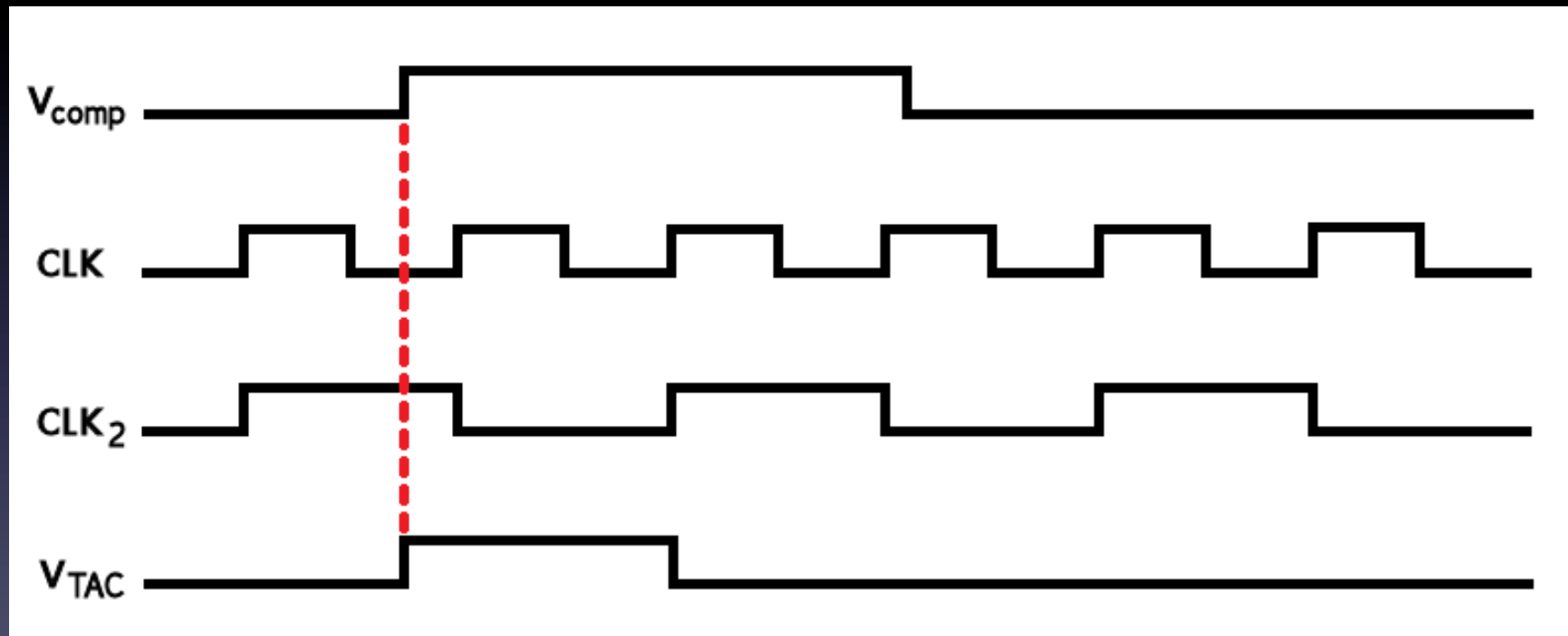
TDC Introduction

- Accurate time measuring (binning ~ 100 ps)
- Prototype under testing
- Study the implementation with a new cheaper 0.11 μm technology

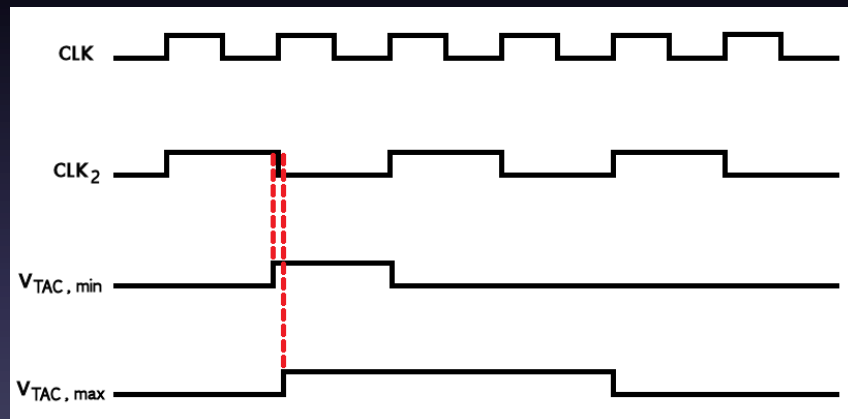
TDC Implementation



TDC Principles (1)



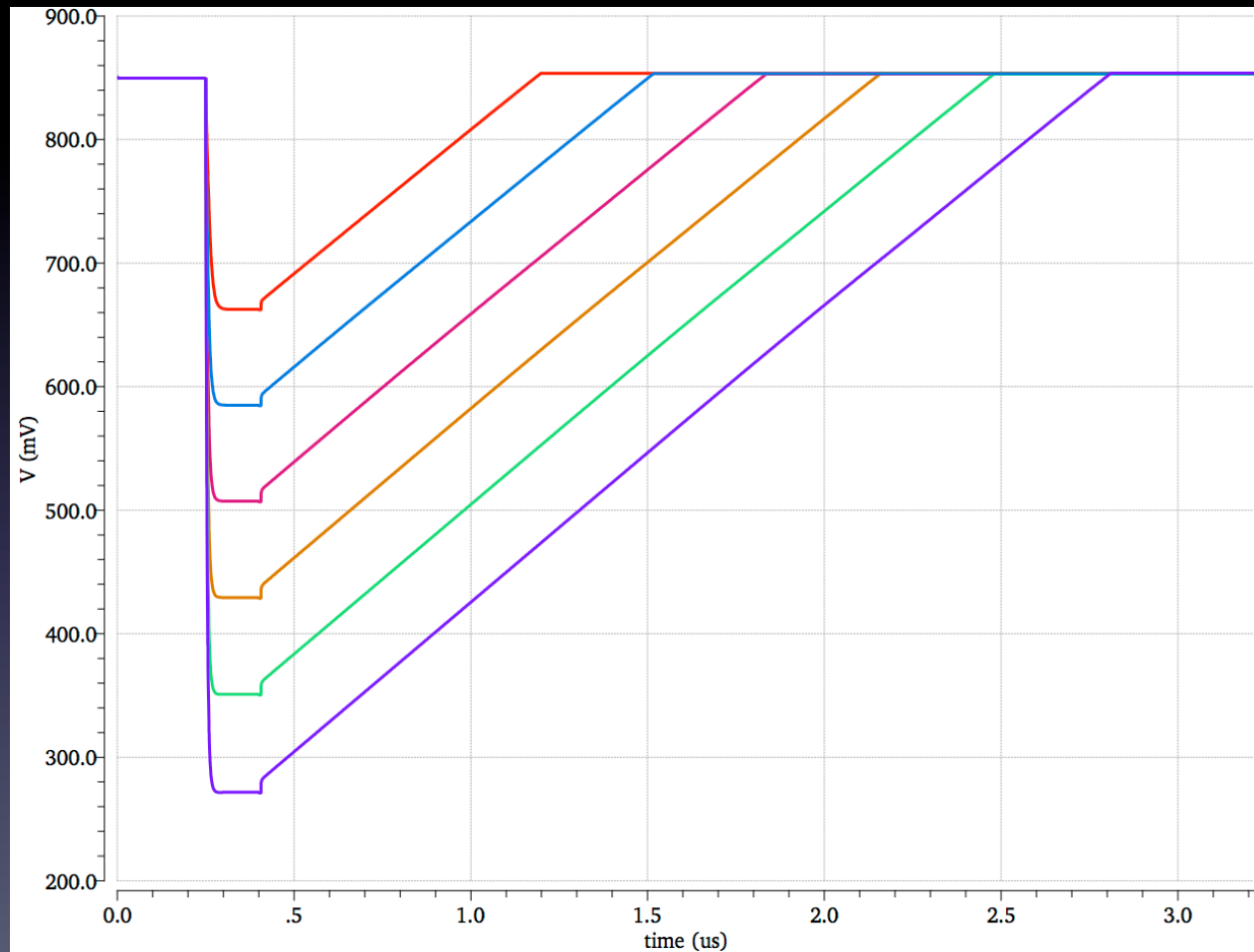
TDC Principles (2)



- $T_{\text{CLK}} < t_{\text{TAC}} < 3 T_{\text{CLK}}$
- Binning ~ 50 ps

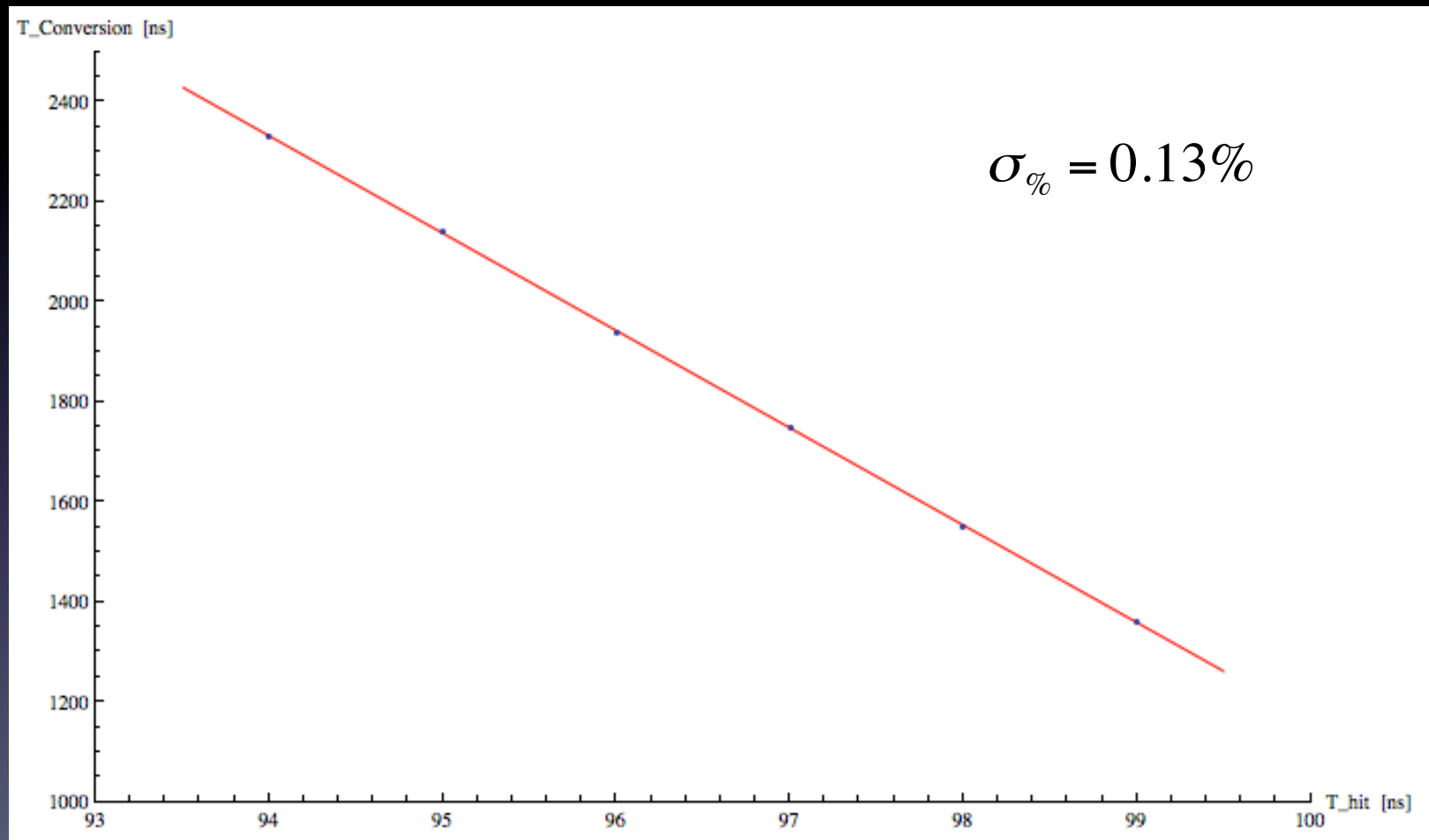
$$T_r = \frac{I_1 C_2}{I_2 C_1} t_{\text{TAC}}$$

Simulations: TDC Linearity (1)



Simulations by Alberto Riccardi

Simulations: TDC Linearity (2)



Simulations by Alberto Riccardi

Conclusions and perspectives

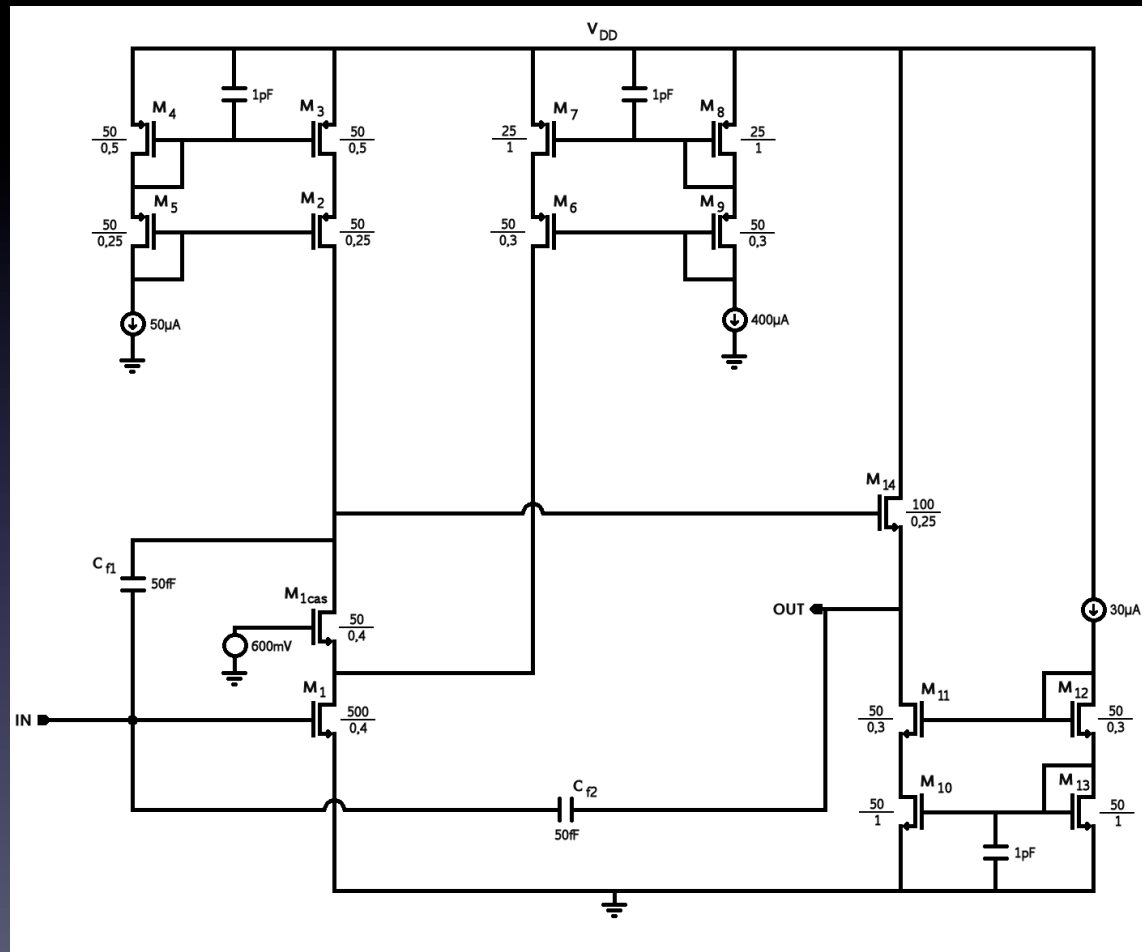
- Matching between electronics and physics simulations
- Improvement of the ToT stage output linearity
- Topology adjustment to process signals of both polarities
- Improvement of the TDC flexibility
- Combined simulations FE+TDC
- Layout design



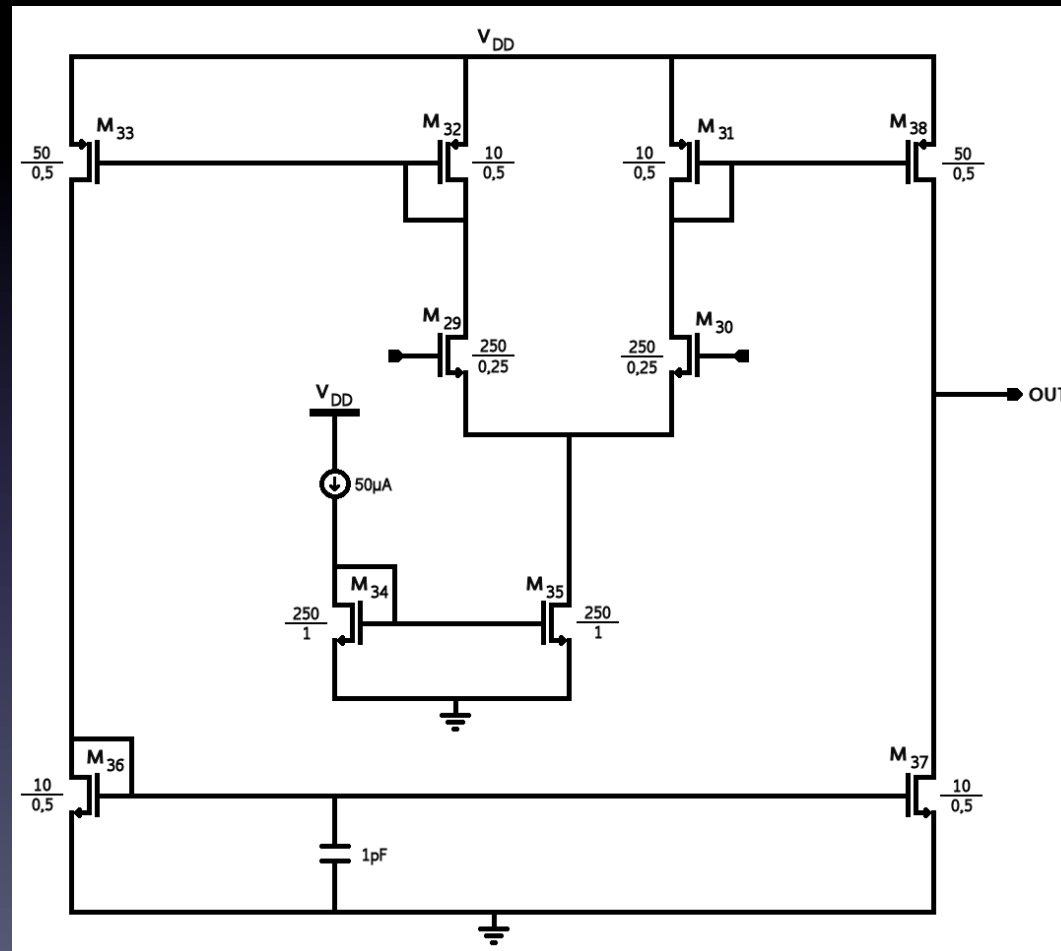
*Thank you for your
kind attention*

Backup Slides

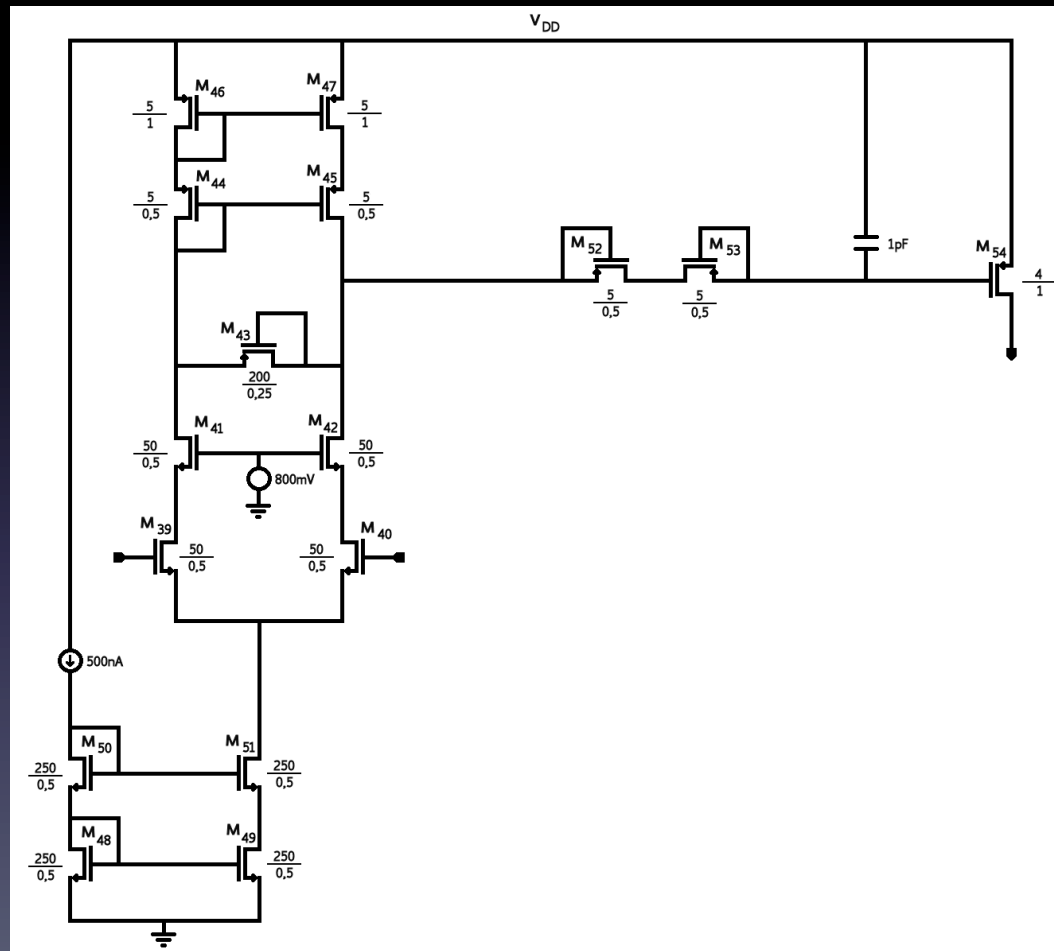
CSA schematic



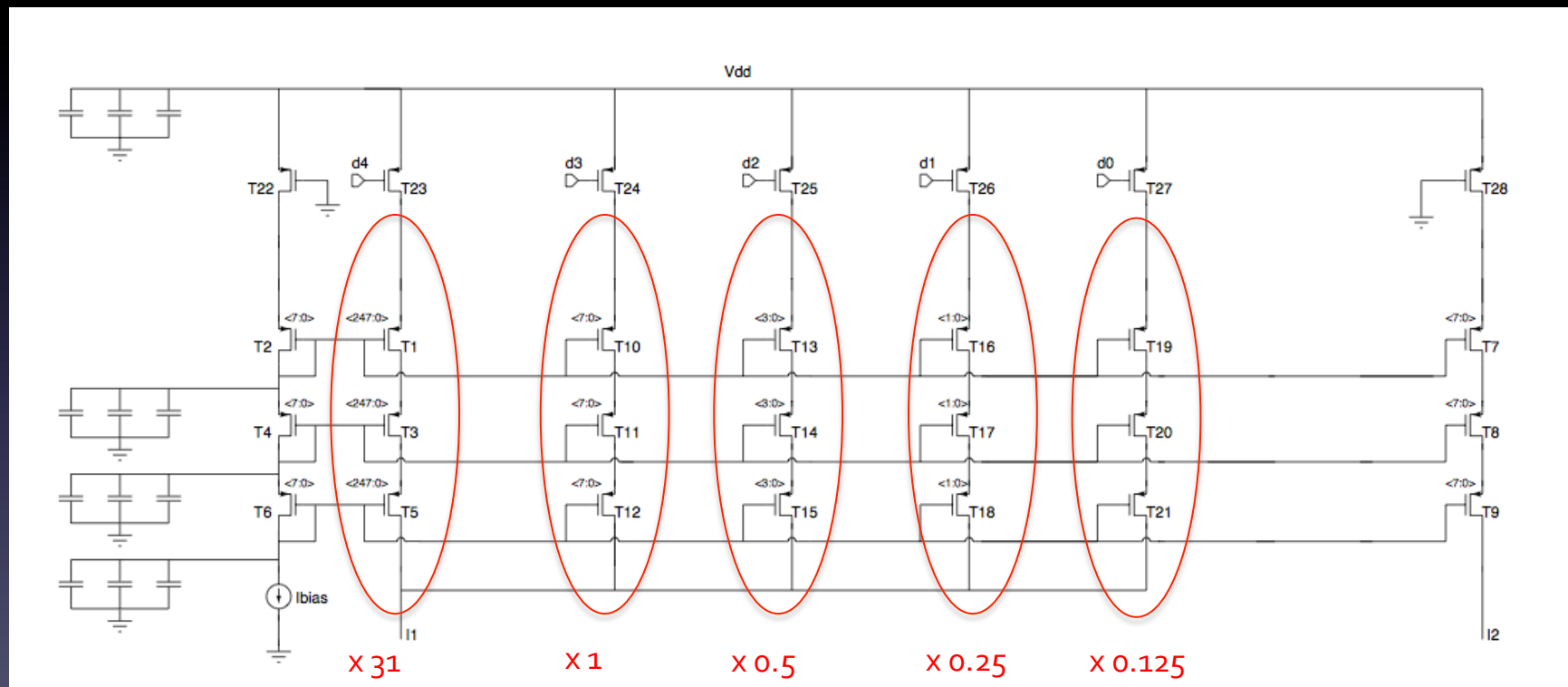
ToT Amplifier schematic



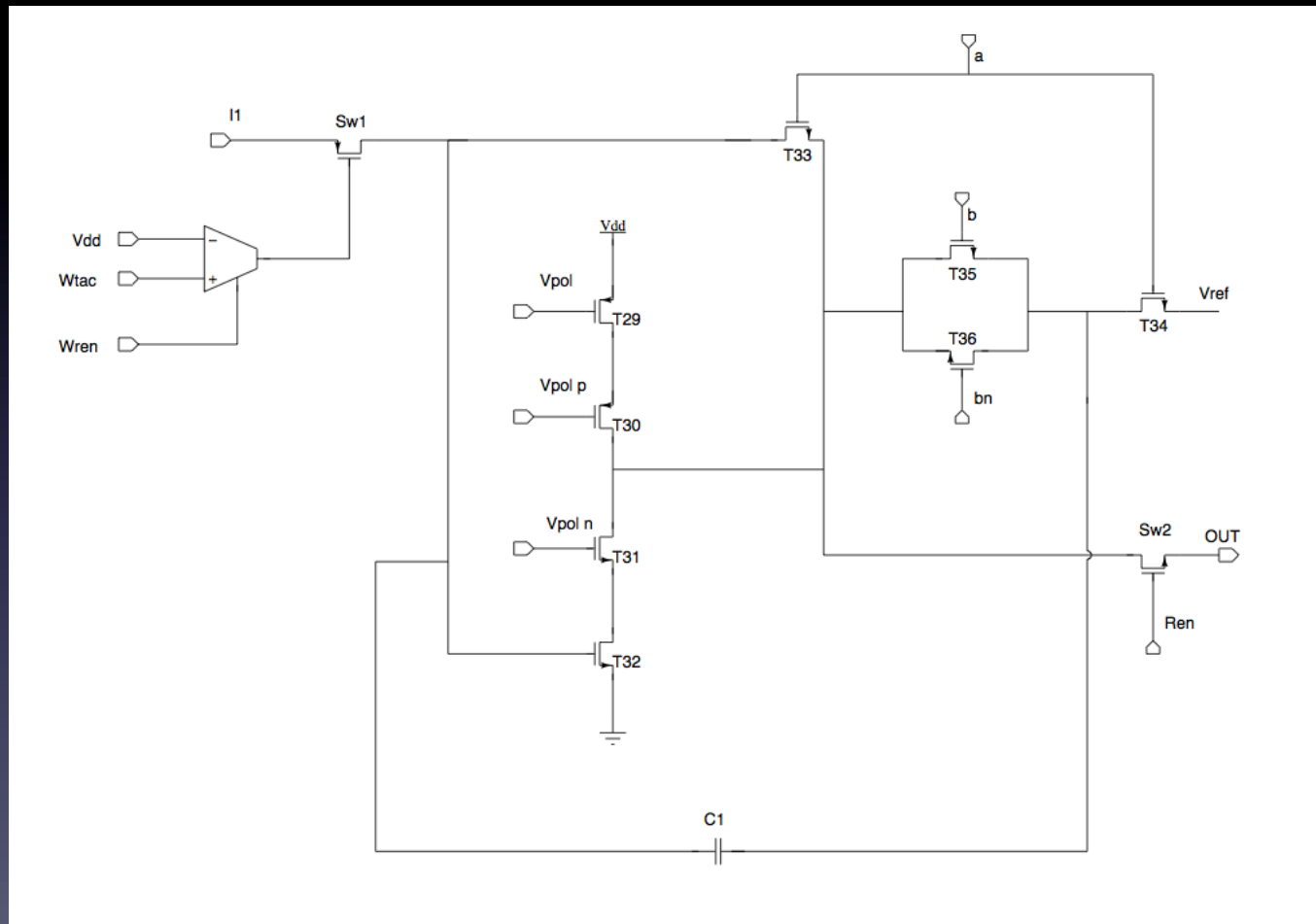
Baseline Holder schematic



Current Source



Time to Amplitude Converter




Implemented pole-zero cancellation

- $$\left(R_f\right)_{eq} = \frac{v_{preamp}}{I_f} = \left(\frac{g_{m17}}{g_{m16}}\right) \cdot \frac{1}{g_{m15}}$$

- $$\left(R_x\right)_{eq} = \frac{v_{out}}{I_{out}} = \left(\frac{g_{m17}}{g_{m18}}\right) \cdot \frac{1}{g_{m15}}$$

- $$\frac{g_{m17}}{g_{m16}} = 80$$

- $$\frac{g_{m17}}{g_{m18}} = 2$$


$$\frac{\left(R_f\right)_{eq}}{\left(R_x\right)_{eq}} = \frac{C_{pz}}{C_f} = 40$$

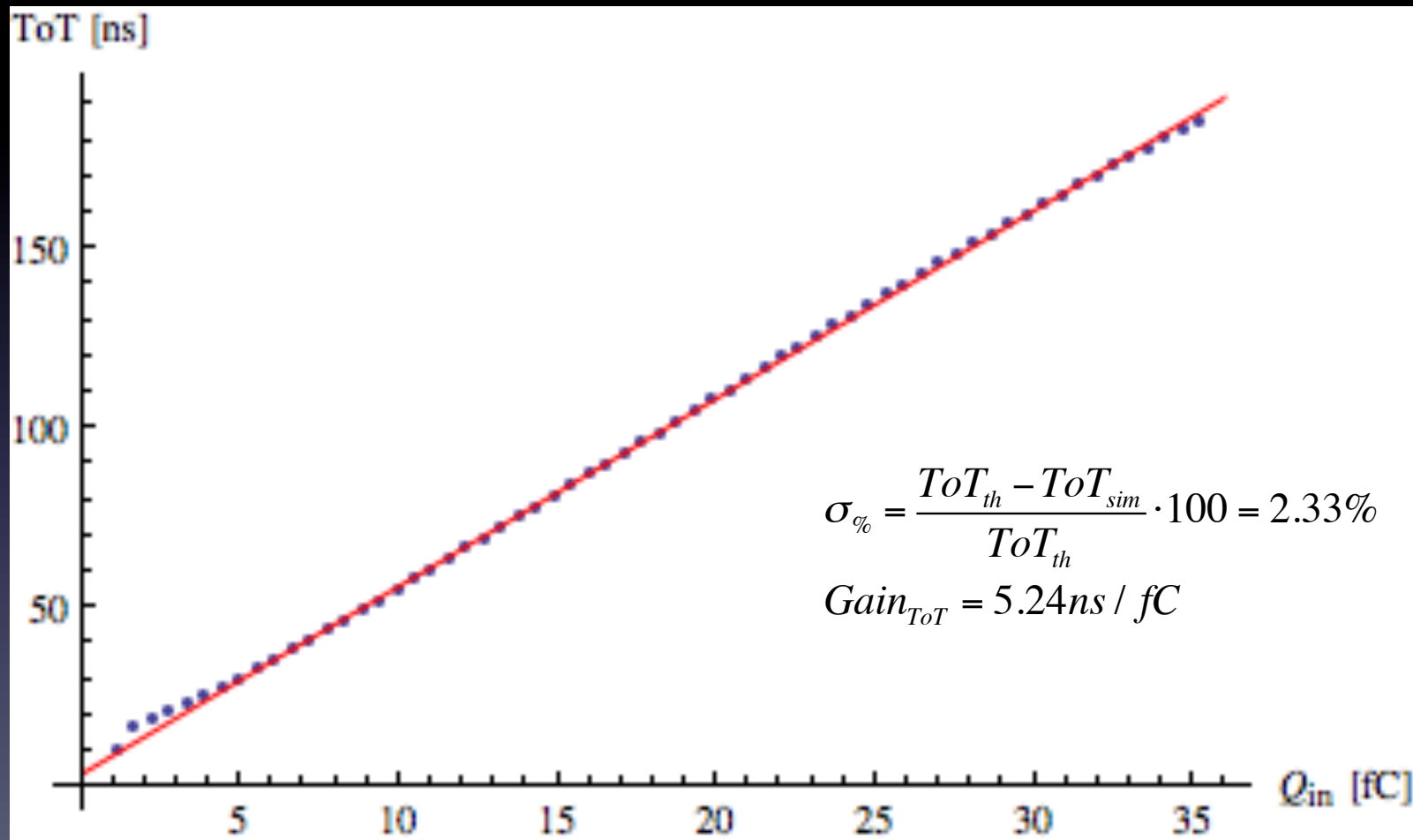
Simulations: FE performances

$$C_{\text{det}} = 5 \text{ pF}$$

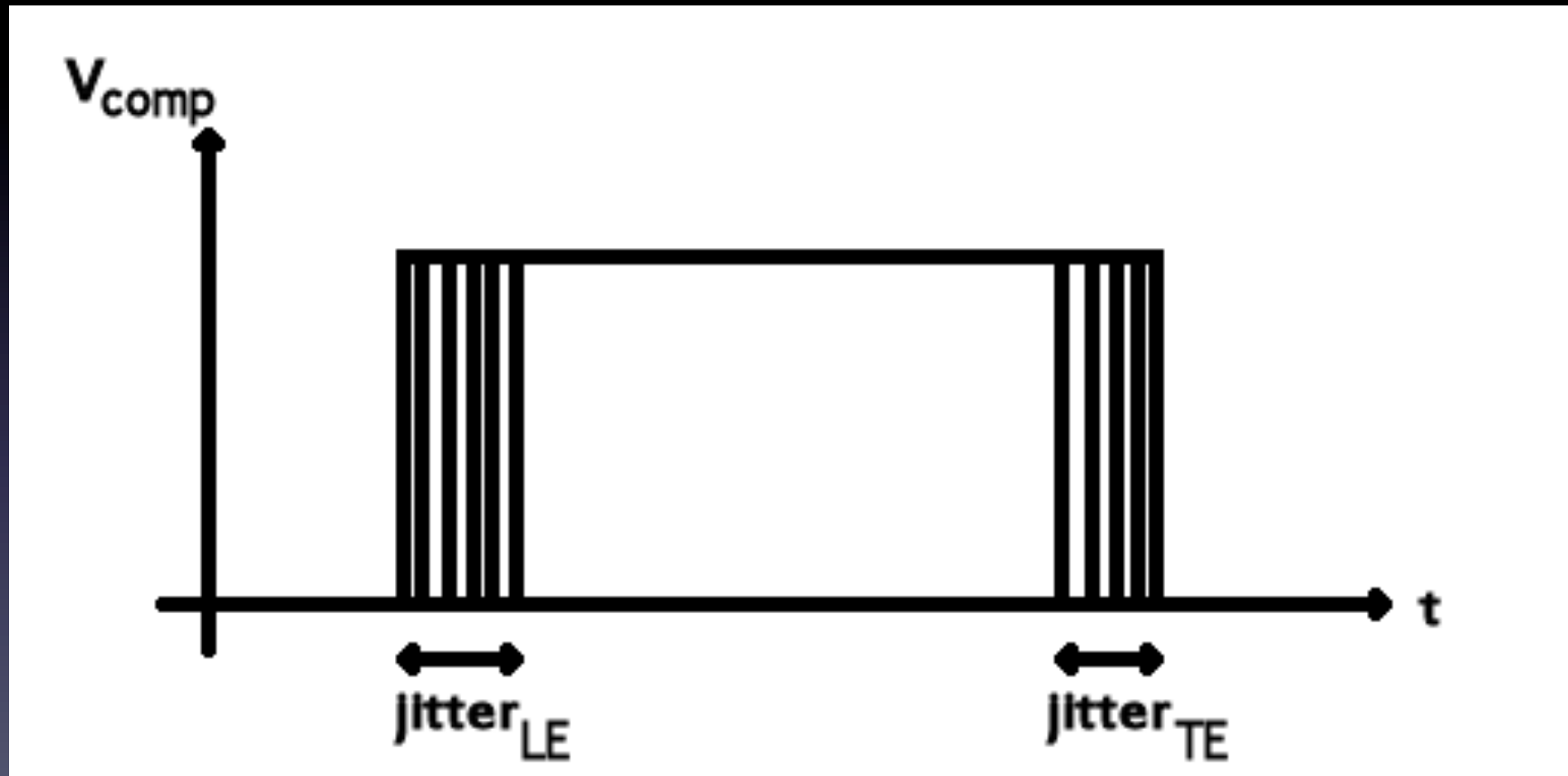
$$C_{\text{det}} = 30 \text{ pF}$$

- ToT stage gain $\sim 32 \text{ mV/fC}$
 - SNR ($Q_{\text{in}} = 4 \text{ fC}$) ~ 117
- ToT stage gain $\sim 19 \text{ mV/fC}$
 - SNR ($Q_{\text{in}} = 4 \text{ fC}$) ~ 26

Simulations: Linearity

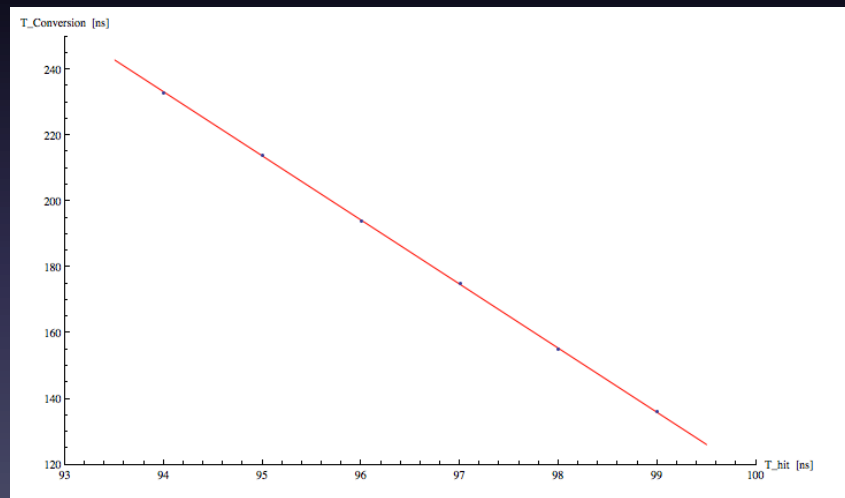


Simulations: Jitter (1)

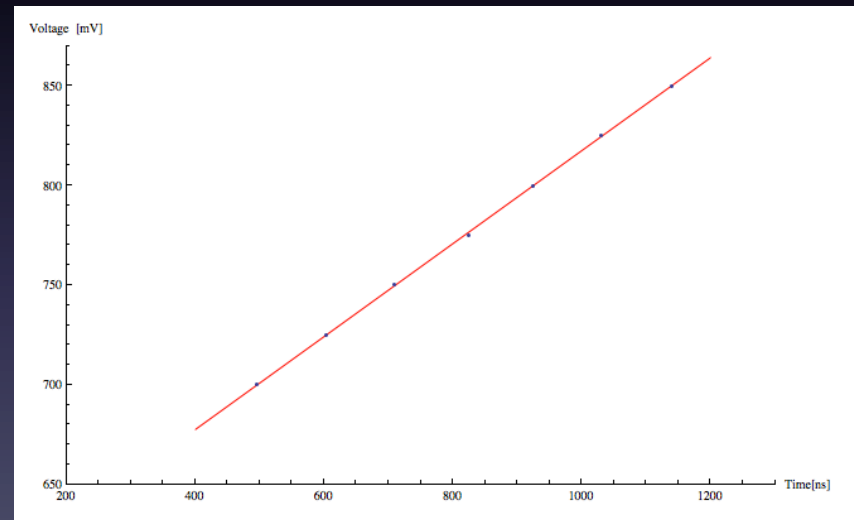


TDC Linearity

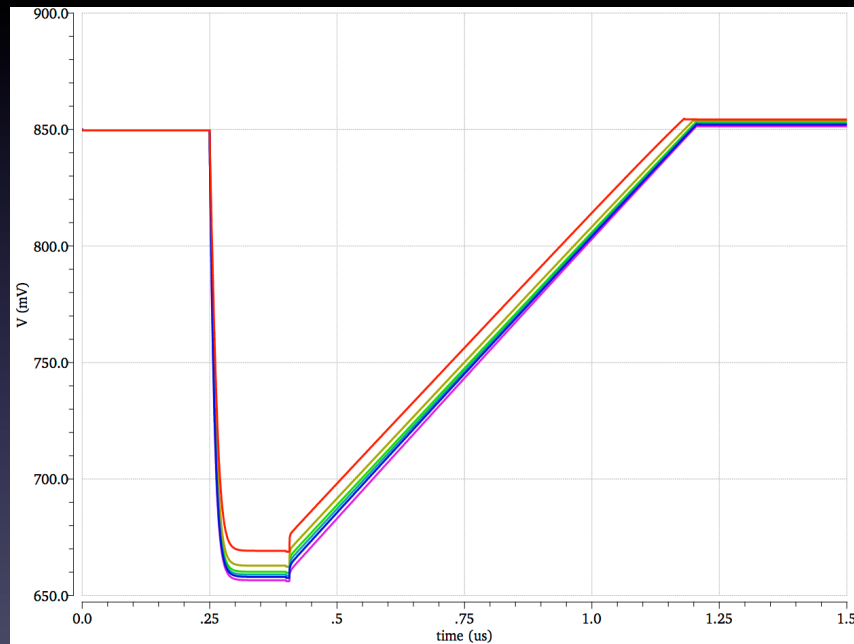
Discharging phase



Recharging phase

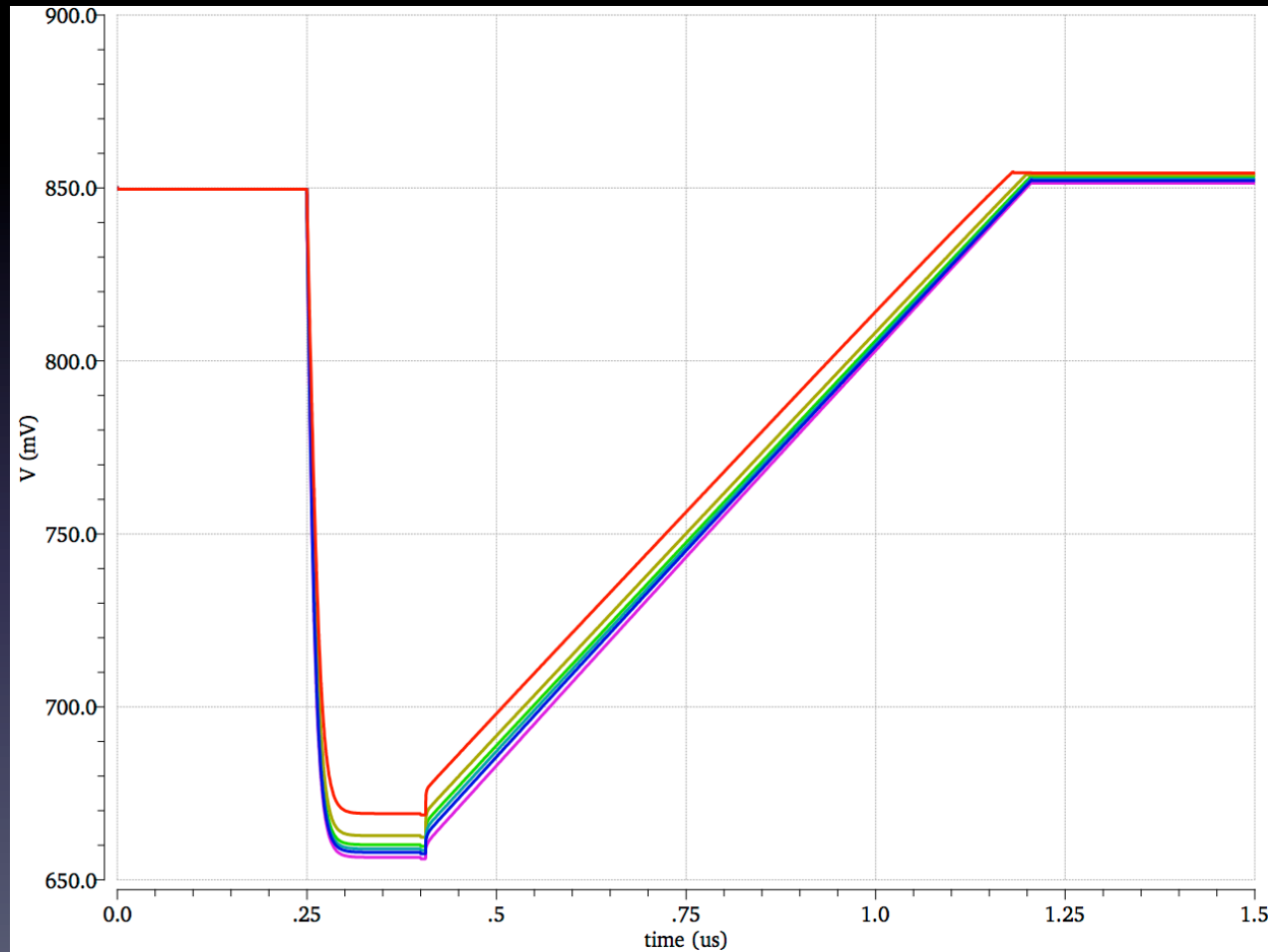


Simulations: Temperature variations

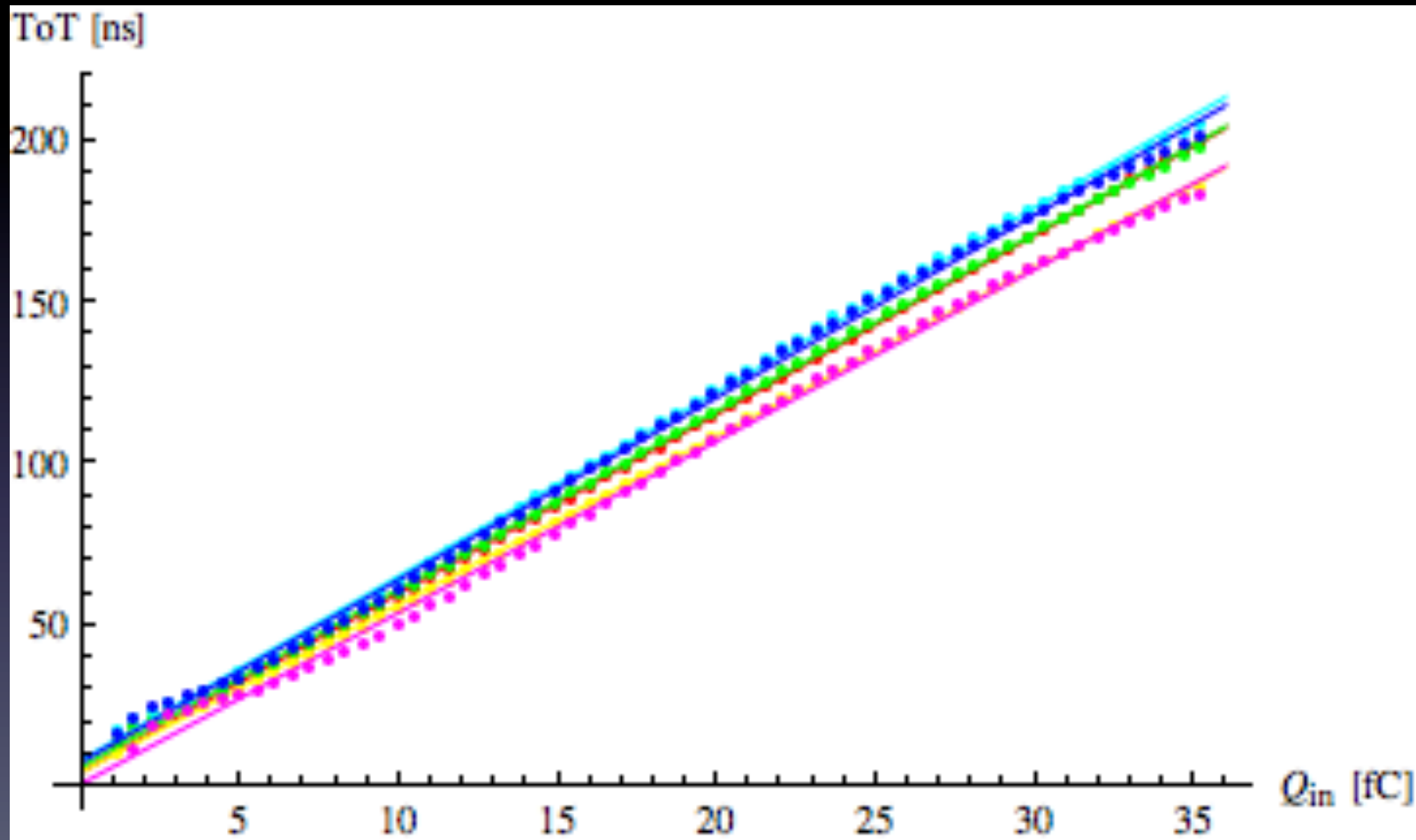


Temperature [°C]	Time of conversion
0	0010111101
25	0011000000
50	0011000001
75	0011000001
100	0011000001
125	0011000001

TDC Temperature variations

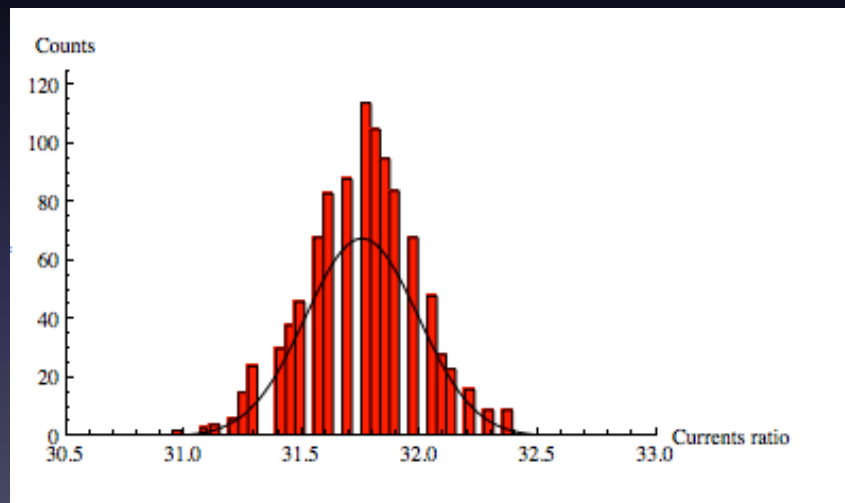


FE Temperature variations



A vs B Technologies

A Technology



B Technology

